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Data Sheet

August 14, 2026

EXFO

Exfo WA-1000 Laser Wavelength Meter

The EXFO WA-1000 Wavemeter measures absolute CW laser wavelength using a scanning Michelson interferometer referenced to a multi-mode HeNe standard. OEM SPWA1000/1500 datasheet lists absolute accuracy ± 1.0 ppm (± 0.001 nm at 1000 nm), display resolution 0.001 nm, VIS/NIR/IR range options, optical sensitivity 20 uW (VIS/NIR) or 1 mW (IR), and 4 measurements/s update rate. CW laser absolute wavelength verification in R&D and manufacturing, tunable laser characterization, and wavelength setpoint deviation monitoring via analog output. Beam Height: 165 mm plus or minus 6 mm adjustable. Analog Output: plus or minus 5 V proportional to wavelength deviation. Accuracy Bandwidth Condition: laser spectral bandwidth less than 10 GHz FWHM. From EXFO WA-1000/WA-1500 Laser Wavelength Meters specification sheet SPWA1000/1500.4AN. WA-1500 improves absolute accuracy to ± 0.2 ppm; confirm VIS/NIR or IR configuration on the unit.



MODEL

Exfo WA-1000

CALIBRATION

Available on request

CONDITION

Used

STATUS

In stock

RFQ / SKU

WA-1000

LISTING

<https://aumictechlabs.com/products/wa-1000-2/>

NIST-traceable cal

SAM registered

30-day returns

NAICS 423690 · 811210 · 541380

This unit

The EXFO WA-1000 is a precision laser wavelength meter employing a scanning Michelson interferometer with built-in HeNe laser reference standard for absolute wavelength measurement of continuous wave (CW) sources. It delivers ± 1.0 ppm accuracy (± 0.001 nm at 1000 nm) for laser spectral bandwidth below 10 GHz FWHM, with automatic atmospheric correction via

integrated temperature and pressure sensors. Technical Specifications Measurement Principle: Scanning Michelson interferometer comparing input laser interference fringe pattern against internal HeNe reference (± 500 MHz or ± 1 ppm absolute accuracy). Wavelength Ranges (detector/beamsplitter selectable): Visible (VIS): 400 nm to 1100 nm Near Infrared (NIR): 600 nm to 1800 nm Infrared (IR): 1500 nm to 4000 nm Display: Nanometers (nm), wavenumbers (cm^{-1}), or frequency (GHz) in air or vacuum reference. Resolution: 0.001 nm / 0.001 cm^{-1} / 0.1 GHz. Measurement Rate: 4.0 Hz (VIS, NIR); 2.5 Hz (IR). Optical Input Sensitivity: VIS/NIR: 20 μW minimum; 2 mW maximum IR: 1.0 mW minimum; 100 mW maximum Dynamic Range: 400:1 with automatic attenuator (0–2 Optical Density). Environmental Compensation: Continuous refractive index correction for air conditions. Key Features Built-in HeNe reference laser (Class 2, 633 nm, 1 mW max) enables continuous self-calibration Automatic intensity control across wide input power range Internal temperature and pressure sensors eliminate atmospheric measurement drift Multiple display units and resolution for research, manufacturing, and telecommunications workflows Typical Applications Laser source characterization in telecommunications, research laboratories, and precision manufacturing environments requiring traceable absolute wavelength verification. Compatibility & Integration Interfaces: RS-232 serial (standard); GPIB/IEEE-488 (optional). Inputs: FC/PC fiber connector (FC/APC optional) for VIS/NIR; free-space beam input (2 mm aperture) with red alignment tracer. Outputs: Analog monitor signal (fringes, timing) for oscilloscope display; ± 5 V analog output proportional to wavelength deviation from setpoint.

Features & description

From manufacturer datasheet

Built-in HeNe wavelength standard

VIS NIR and IR detector/beamsplitter versions Fiber FC/PC and free-space inputs RS-232 and analog deviation output Technical Specifications Absolute Accuracy: plus or minus 1.0 ppm Absolute Accuracy At 1000 nm: plus or minus 0.001 nm Absolute Accuracy Wavenumber At 10000 per cm: plus or minus 0.01 per cm Absolute Accuracy Frequency At 300000 GHz: plus or minus 0.3 GHz Display Resolution Wavelength: 0.001 nm Display Resolution Wavenumber: 0.01 per cm Display Resolution Frequency: 0.1 GHz Wavelength Range VIS: 400 to 1100 nm Wavelength Range NIR: 600 to 1800 nm Wavelength Range IR: 1.5 to 4.0 μ m Optical Sensitivity VIS NIR: 20 μ W Optical Sensitivity IR: 1 mW Maximum Input VIS NIR: 2 mW Maximum Input IR: 100 mW Measurement Update Time: 0.25 s (4 measurements/s) Optical Fiber Input: FC/PC Free Space Aperture: collimated beam 2 mm diameter Beam Height: 165 mm plus or minus 6 mm adjustable Instrument Interface: RS-232 Analog Output: plus or minus 5 V proportional to wavelength deviation Size HxWxD: 20.3 cm x 38.9 cm x 29.2 cm Weight: 11.3 kg Power: 100 to 240 VAC 50/60 Hz Accuracy Bandwidth Condition: laser spectral bandwidth less than 10 GHz FWHM Notes From EXFO WA-1000/WA-1500 Laser Wavelength Meters specification sheet SPWA1000/1500.4AN. WA-1500 improves absolute accuracy to +/-0.2 ppm; confirm VIS NIR or IR configuration on the unit.

WA1000 Characteristics / Specifications

PARAMETER	VALUE
Absolute Accuracy	plus or minus 1.0 ppm
Absolute Accuracy At 1000 nm	plus or minus 0.001 nm
Absolute Accuracy Wavenumber At 10000 per cm	plus or minus 0.01 per cm
Absolute Accuracy Frequency At 300000 GHz	plus or minus 0.3 GHz
Display Resolution Wavelength	0.001 nm
Display Resolution Wavenumber	0.01 per cm
Display Resolution Frequency	0.1 GHz
Wavelength Range VIS	400 to 1100 nm
Wavelength Range NIR	600 to 1800 nm
Wavelength Range IR	1.5 to 4.0 um
Optical Sensitivity VIS NIR	20 uW
Optical Sensitivity IR	1 mW
Maximum Input VIS NIR	2 mW
Maximum Input IR	100 mW
Measurement Update Time	0.25 s (4 measurements/s)
Optical Fiber Input	FC/PC
Free Space Aperture	collimated beam 2 mm diameter
Beam Height	165 mm plus or minus 6 mm adjustable
Instrument Interface	RS-232
Analog Output	plus or minus 5 V proportional to wavelength deviation
Size HxWxD	20.3 cm x 38.9 cm x 29.2 cm
Weight	11.3 kg
Power	100 to 240 VAC 50/60 Hz
Accuracy Bandwidth Condition	laser spectral bandwidth less than 10 GHz FWHM

PARAMETER	VALUE
Wavelength range	VIS: 400 to 1100 nm
Bandwidth	Condition: laser spectral bandwidth less than 10 GHz FWHM

Full OEM specifications

Complete technical content extracted from the manufacturer datasheet. Sparse OEM tables are reconstructed as tables below; other text is preserved as paragraphs.

Specifications	
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PARAMETER	VALUE
Absolute Accuracy	plus or minus 1.0 ppm
Absolute Accuracy At 1000 nm	plus or minus 0.001 nm
Absolute Accuracy Wavenumber At 10000 per cm	plus or minus 0.01 per cm
Absolute Accuracy Frequency At 300000 GHz	plus or minus 0.3 GHz
Display Resolution Wavelength	0.001 nm
Display Resolution Wavenumber	0.01 per cm
Display Resolution Frequency	0.1 GHz
Wavelength Range VIS	400 to 1100 nm
Wavelength Range NIR	600 to 1800 nm
Wavelength Range IR	1.5 to 4.0 um
Optical Sensitivity VIS NIR	20 uW
Optical Sensitivity IR	1 mW
Maximum Input VIS NIR	2 mW
Maximum Input IR	100 mW
Measurement Update Time	0.25 s (4 measurements/s)
Optical Fiber Input	FC/PC
Free Space Aperture	collimated beam 2 mm diameter
Beam Height	165 mm plus or minus 6 mm adjustable
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Analog Output	plus or minus 5 V proportional to wavelength deviation
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Notes

From EXFO WA-1000/WA-1500 Laser Wavelength Meters specification sheet SPWA1000/1500.4AN. WA-1500 improves absolute accuracy to ± 0.2 ppm; confirm VIS NIR or IR configuration on the unit.

Available from Aumictech

Used and refurbished unit evaluated in-house. Calibration: Available on request. Used · In stock.

Request a quote: sales@aumictech.com · +1 (484) 841-9341

Aumictech

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NIST-traceable calibration · SAM registered ·
30-day returns
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Technical content from manufacturer specifications. Unit photo/stock from Aumictech listing when available. Specifications subject to OEM documentation and unit condition.